

GL Silicon N-Channel Power MOSFET

General Description :

The GL10N08-8 uses advanced trench technology and design to provide excellent RDS(ON) with low gate charge. It can be used in a wide variety of applications. The package form is SOP-8, which accords with the RoHS standard.

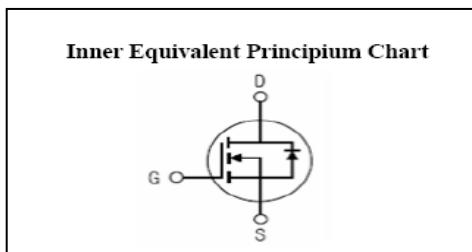
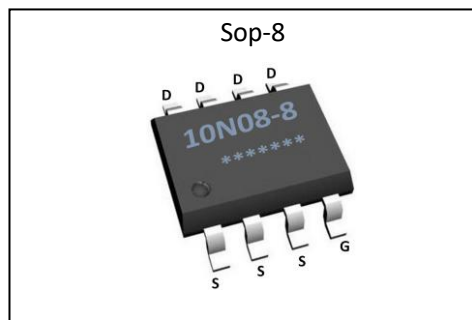
Features :

- Fast Switching
- Low Gate Charge and $R_{ds(on)}$
- Low Reverse transfer capacitances
- 100% Single Pulse avalanche energy Test

Applications :

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply

V_{DSS}	80	V
I_D	10	A
P_D	3.0	W
$R_{DS(ON)}$ type	13	mΩ



Absolute ($T_c = 25^\circ\text{C}$ unless otherwise specified) :

Symbol	Parameter	Rating	Units
V_{DSS}	Drain-to-Source Voltage	80	V
I_D	Continuous Drain Current	10	A
	Continuous Drain Current $T_c = 100^\circ\text{C}$	8	A
I_{DM}	Pulsed Drain Current	120	A
V_{GS}	Gate-to-Source Voltage	± 20	V
E_{AS}^{a2}	Single Pulse Avalanche Energy	105	mJ
E_{AR}^{a1}	Avalanche Energy ,Repetitive	15	mJ
I_{AR}^{a1}	Avalanche Current	45	A
$\frac{dv}{dt}_{a3}$	Peak Diode Recovery dv/dt	5.0	V/ns
P_D	Power Dissipation	3.0	W
T_J, T_{stg}	Operating Junction and Storage Temperature Range	175 , -55 to 175	$^\circ\text{C}$
T_L	MaximumTemperature for Soldering	300	$^\circ\text{C}$

**Electrical Characteristics** ($T_c = 25^\circ\text{C}$ unless otherwise specified) :

OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
V_{DSS}	Drain to Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	80	--	--	V
$\Delta BV_{DSS}/\Delta T_J$	Bvdss Temperature Coefficient	$I_D=250\mu A, \text{Reference } 25^\circ\text{C}$	--	0.1	--	$V/^\circ\text{C}$
I_{DSS}	Drain to Source Leakage Current	$V_{DS}=80V, V_{GS}=0V, T_a=25^\circ\text{C}$	--	--	1	μA
		$V_{DS}=64V, V_{GS}=0V, T_a=125^\circ\text{C}$	--	--	250	
$I_{GSS(F)}$	Gate to Source Forward Leakage	$V_{GS}=+20V$	--	--	1	μA
$I_{GSS(R)}$	Gate to Source Reverse Leakage	$V_{GS}=-20V$	--	--	-1	μA

ON Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$R_{DS(ON)}$	Drain-to-Source On-Resistance	$V_{GS}=10V, I_D=10A$	--	13	16	$m\Omega$
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	1.0	1.7	2.5	V
Pulse width $t_p \leq 380\mu s, \delta \leq 2\%$						

Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
g_{fs}	Forward Transconductance	$V_{DS}=5V, I_D=10A$	20	--	--	S
C_{iss}	Input Capacitance	$V_{GS}=0V, V_{DS}=40V$ $f=1.0\text{MHz}$	--	2200	--	pF
C_{oss}	Output Capacitance		--	290	--	
C_{rss}	Reverse Transfer Capacitance		--	130	--	

Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$t_{d(ON)}$	Turn-on Delay Time	$I_D=10A, V_{DD}=40V$ $V_{GS}=10V, R_G=3.0\Omega$	--	15	--	ns
t_r	Rise Time		--	10	--	
$t_{d(OFF)}$	Turn-Off Delay Time		--	35	--	
t_f	Fall Time		--	18	--	
Q_g	Total Gate Charge	$I_D=10A, V_{DD}=40V$ $V_{GS}=10V$	--	50	--	nC
Q_{gs}	Gate to Source Charge		--	6.0	--	
Q_{gd}	Gate to Drain ("Miller") Charge		--	13.5	--	

Source-Drain Diode Characteristics

Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
I_S	Continuous Source Current (Body Diode)		--	--	10	A
I_{SM}	Maximum Pulsed Current (Body Diode)		--	--	120	A
V_{SD}	Diode Forward Voltage	$I_S = 10A, V_{GS} = 0V$	--	--	1.5	V
t_{rr}	Reverse Recovery Time	$I_S = 10A, T_j = 25^\circ C$	--	47	--	ns
Q_{rr}	Reverse Recovery Charge	$di_F/dt = 100A/\mu s, V_{GS} = 0V$	--	60	--	nC

Pulse width $t_p \leq 380\mu s, \delta \leq 2\%$

Symbol	Parameter	Typ.	Units
$R_{\theta JA}$	Junction-to-Ambient	42	$^\circ C/W$

^{a1} : Repetitive rating; pulse width limited by maximum junction temperature

^{a2} : EAS condition : $T_j = 25^\circ C$, $V_{DD} = 40V, V_G = 10V, L = 0.5mH, R_g = 25\Omega$

^{a3} : $I_{SD} = 10A, di/dt \leq 100A/\mu s, V_{DD} \leq BV_{DS}$, Start $T_j = 25^\circ C$

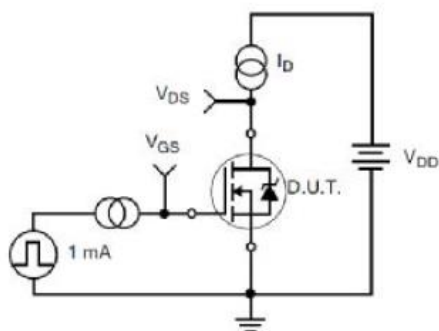
Test Circuit and Waveform


Figure 17. Gate Charge Test Circuit

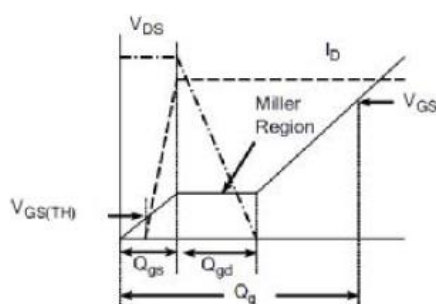


Figure 18. Gate Charge Waveform

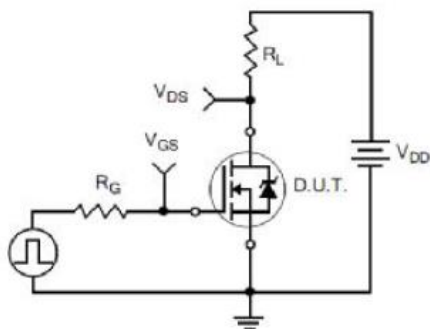


Figure 19. Resistive Switching Test Circuit

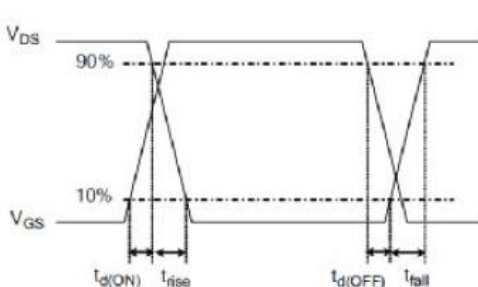
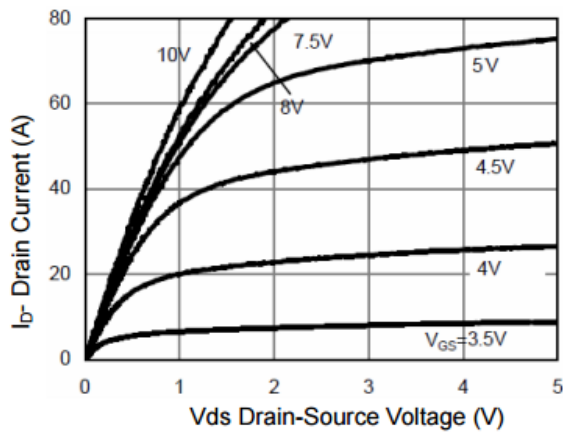
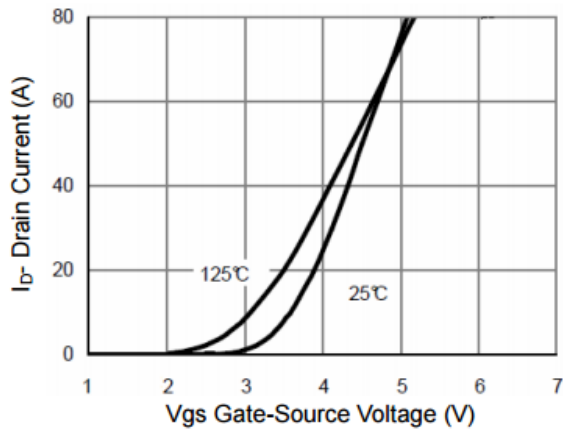
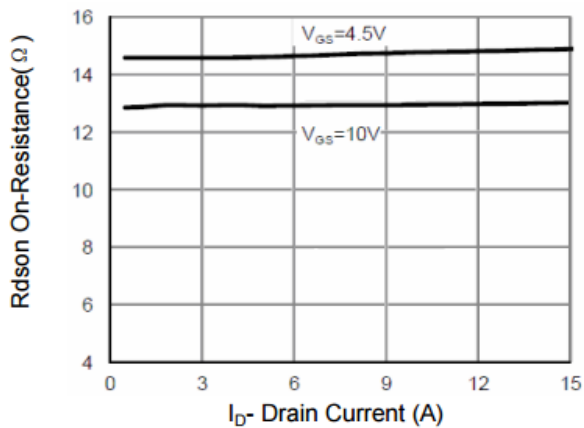
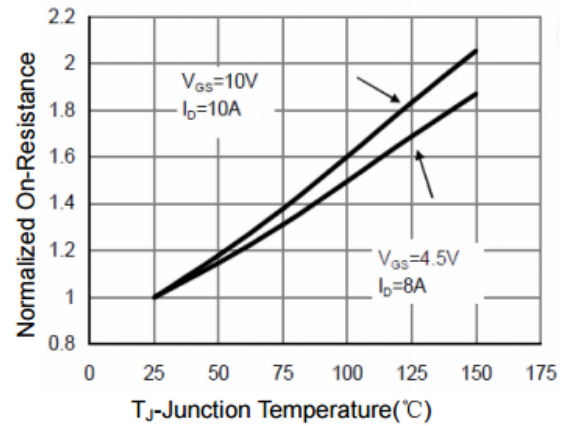
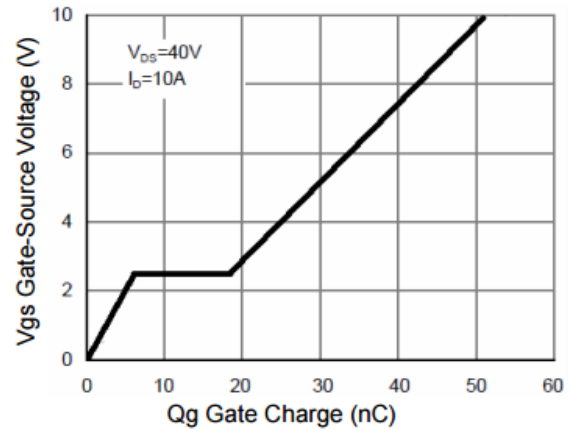
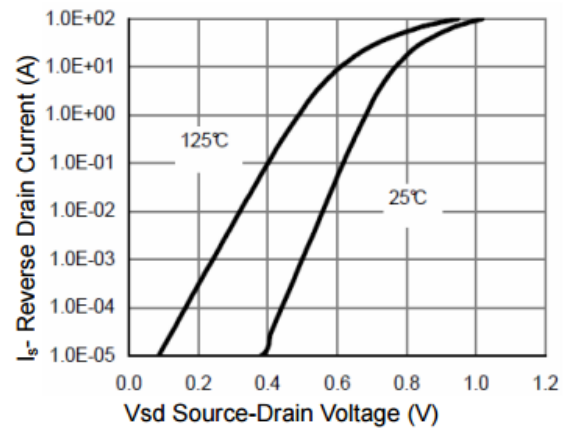
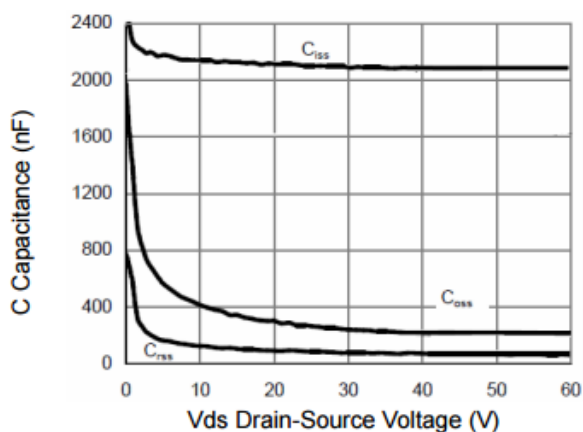
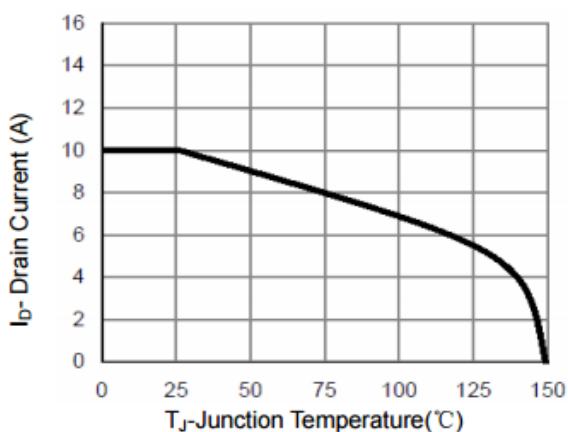
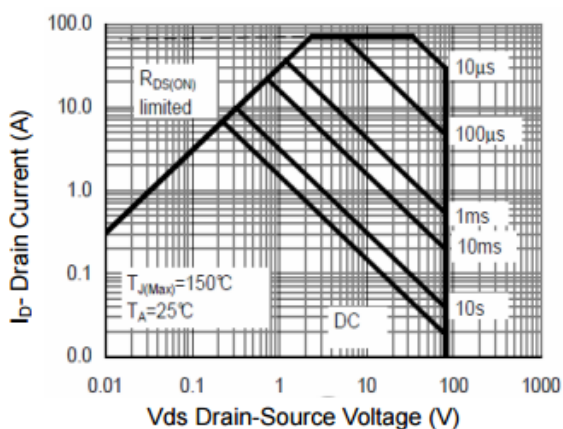
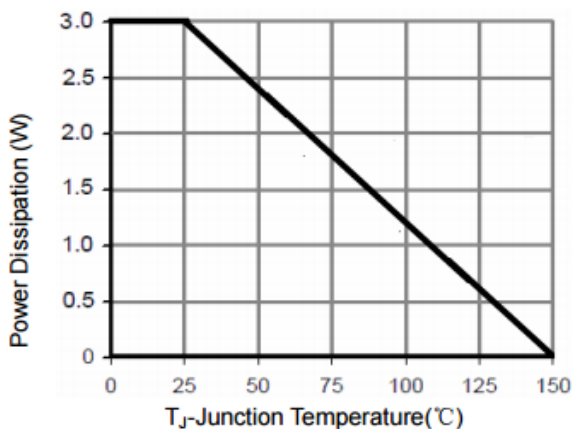
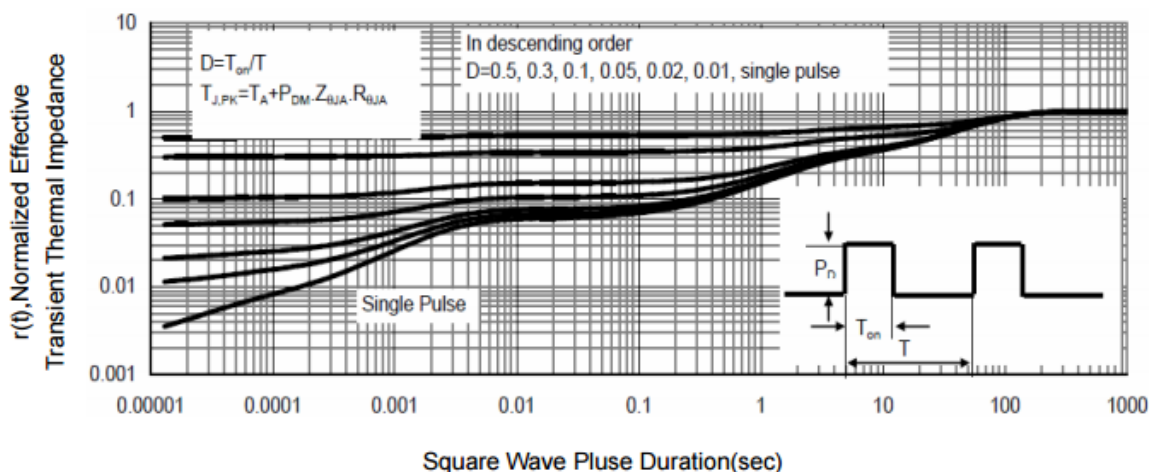


Figure 20. Resistive Switching Waveforms

GL Silicon N-Channel Power MOSFET
Typical Electrical and Thermal Characteristics (Curves)

Figure 1 Output Characteristics

Figure 2 Transfer Characteristics

Figure 3 Rdson- Drain Current

Figure 4 Rdson-Junction Temperature

Figure 5 Gate Charge

Figure 6 Source- Drain Diode Forward

**GL10N08-8**

无锡光磊电子科技有限公司

GL Silicon N-Channel Power MOSFET**Figure 7 Capacitance vs Vds****Figure 9 Current De-rating****Figure 8 Safe Operation Area****Figure 10 Power De-rating****Figure 11 Normalized Maximum Transient Thermal Impedance**

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